TENTATIVE

TOSHIBA GaAs LINEAR INTEGRATED CIRCUIT GaAs MONOLITHIC

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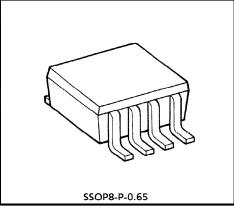
1.9GHz POWER AMP

FEATURES

- $V_{DD} = 3V$, $I_{DD} = 130 \text{mA}$ (Typ.)
- $P_o = 21dBmW (Min), G_p = 22dB (Typ.)$
- Single voltage supply

MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Supply Voltage	V_{DD}	5	V
Supply Voltage	V_{GG}	3	V
Input Power	Pi	10	mW
Power Dissipation	Pd (*)	250	mW
Operating Temperature Range	Topr	- 40∼85	°C
Storage Temperature Range	T _{stg}	- 55∼150	°C



Weight: 0.02g (Typ.)

Pd (*) When mounted on 2.5cm2 x 1.6t glass epoxy board. $V_{DD} = V_{DD1} = V_{DD2}$

ELECTRICAL CHARACTERISTICS (V_{DD} = 3V, I_{DD} = 130mA (Note 1), 1/8 duty operation) $(f = 1.9GHz, Ta = 25^{\circ}C)$

CHARACTERISTIC	SYMBOL	TEST CIR- CUIT	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Output Power	Po	_	P _i = 1dBmW	21	_	_	dBmW
Small Signal Gain	Gp	_	_	20	22	_	dB
Adjacent Channel Leakage Power Ratio	Padj		$P_0 = 21dBmW$, $P_i = Regulation$ $\Delta_f = 600kHz$ (Note 2)	_	_	- 55	dB
Gate Current	lgg	_	$P_0 = 21dBmW$, $P_i = Regulation$	_	_	– 1	mA

DD = DD1 + DD2

Specification when an external match circuit is connected at output.

(Note 1) Value obtained by adjusting (0 to 3V) VGG when 21dBmW is output.

(Note 2) Input signal is modulated to π / GQPSK ($\alpha = 0.5$). Bit rate is 384kbps.

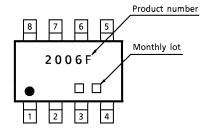
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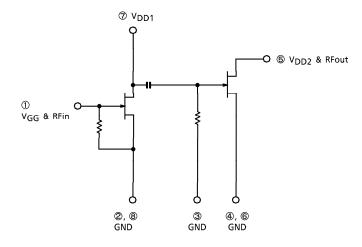
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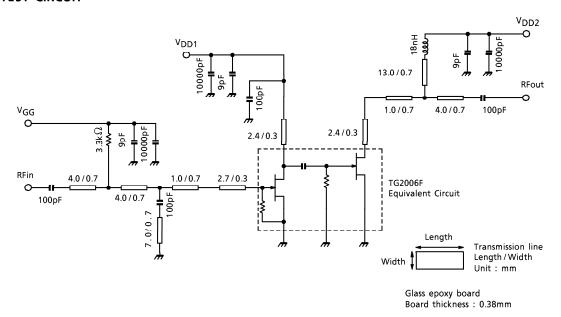
MARKING



EQUIVALENT CIRCUIT



RF TEST CIRCUIT



TG2006F RF TEST BOARD

